

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Donald J. Svetkoff, Donald B. T. Kilgus, Warren Lin, and Jonathan S. Ehrmann

Serial No.: To be Assigned

Filed: Filed Herewith

For: Method And System For High Speed Measuring Of Microscopic Targets

Attorney Docket No.: GSIL 0186 PUS 2

**INFORMATION DISCLOSURE STATEMENT
UNDER 37 C.F.R. § 1.97(b)(1)**

Mail Stop Patent Application
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and § 1.97-1.98, the references listed and identified on the attached Form PTO/SB08A are being submitted herewith for consideration by the Examiner. This Statement is being filed in accordance with 37 C.F.R. § 1.97(b)(1).


While this Statement is being filed in compliance with the duty of disclosure, citation of the attached references is not to be construed as an admission that any of the references are "material" as defined under 37 C.F.R. § 1.56(b).

In accordance with 37 C.F.R. § 1.98(d), copies of the cited references are not being provided since the references were previously cited by or submitted to the Patent and Trademark Office in prior application Serial No. 10/114,750, filed April 2, 2002 (now U.S.P.N. 6,452,686), of which the present application is a continuation.

Respectfully submitted,

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Warren Lin, and Jonathan S. Ehrmann**

Date: March 24, 2004

By: 
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Substitute for Form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Complete if Known	
				Application Number	Unknown
				Filing Date	Herewith
				First Named Inventor	Donald J. Svetkoff et al.
				Group Art Unit	Unknown
				Examiner Name	Unknown
Sheet	1	of	3	Attorney Docket Number	GSIL 0186 PUS 2

U.S. PATENT DOCUMENTS						
Examiner Initials	Cite No. ¹	U.S. PATENT DOCUMENT		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
		3,013,467		Minsky	11-07-1957	
		4,689,491		Lindow, et al.	08-25-1987	
		4,872,125		Goldstein	05-02-1989	
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		5,932,871		Nakagawa, et al.	08- -1999	
		5,594,235		Lee	01-14-1997	

FOREIGN PATENT DOCUMENTS								
Examiner Initials	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Office ³	Number ⁴	Kind Code ⁵ (if known)				

Examiner Signature		Date Considered	
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document.

⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

^a Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ^b Applicant is to place a check mark here if English language Translation is attached.

Substitute for Form 1449B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Complete if Known	
				Application Number	Unknown
				Filing Date	Herewith
				First Named Inventor	Donald J. Svetkoff, et al.
				Group Art Unit	Unknown
				Examiner Name	Unknown
Sheet	3	of	3	Attorney Docket Number	GSIL 0186 PUS 3
OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T ²
		Brochure NM-2654A Panasert IP-K-V, "The Rotating Mirror Scan System Inspects Large High-Density PC Boards Quickly and Precisely", Specifications			
		"Dynamic Focusing in the Confocal Scanning Microscope", T. Wilson and D.K. Hamilton, Journal of Microscopy, Vol. 128, Pt. 2, November 1992, pp. 139-143			
		"Digital Image Processing of Confocal Images", I. J. Cox and C.J.R. Sheppard, Image and Vision Computing, Vol. 1. No. 1, February 1983, pp. 52-56			
		"Three-Dimensional Surface Measurement Using the Confocal Scanning Microscope", D.K. Hamilton and T. Wilson, Appl. Phys. B 27.211-213 (1982)			
		"Scanning Optical Microscope Incorporating A Digital Framestore and Microcomputer", I.J. Cox and C.R. Sheppard. Applied Optics, Vol. 22, No. 10, May 15, 1983, pp. 1474-1478			
		"Depth of Field in the Scanning Microscope", C.J.R. Sheppard and T. Wilson, Optics Letters, September 1978. Vol. 3, No. 3, pp. 115-117			
		"NLB Laser Inspector, NLB-7700M Specifications", Nagoya Electric Works Co., Ltd. December 1994			
		"Automatic Inspection of Component Boards Using 3D and Greyscale Vision", Donald J. Svetkoff, David N. Smith and Brian L. Doss, Proceedings of the 1986 International Symposium on Microelectronics, pp. 57-64			

Examiner Signature		Date Considered	
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